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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	HDMI-CEC, I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I ² S, POR, PWM, WDT
Number of I/O	39
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 13x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-UFQFN Exposed Pad
Supplier Device Package	48-UFQFPN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f051c8u7tr

Contents

1	Introduction	9
2	Description	10
3	Functional overview	13
3.1	ARM [®] -Cortex [®] -M0 core	13
3.2	Memories	13
3.3	Boot modes	13
3.4	Cyclic redundancy check calculation unit (CRC)	14
3.5	Power management	14
3.5.1	Power supply schemes	14
3.5.2	Power supply supervisors	14
3.5.3	Voltage regulator	14
3.5.4	Low-power modes	15
3.6	Clocks and startup	15
3.7	General-purpose inputs/outputs (GPIOs)	16
3.8	Direct memory access controller (DMA)	17
3.9	Interrupts and events	17
3.9.1	Nested vectored interrupt controller (NVIC)	17
3.9.2	Extended interrupt/event controller (EXTI)	17
3.10	Analog-to-digital converter (ADC)	17
3.10.1	Temperature sensor	18
3.10.2	Internal voltage reference (V_{REFINT})	18
3.10.3	V_{BAT} battery voltage monitoring	19
3.11	Digital-to-analog converter (DAC)	19
3.12	Comparators (COMP)	19
3.13	Touch sensing controller (TSC)	19
3.14	Timers and watchdogs	21
3.14.1	Advanced-control timer (TIM1)	21
3.14.2	General-purpose timers (TIM2, 3, 14, 15, 16, 17)	22
3.14.3	Basic timer TIM6	22
3.14.4	Independent watchdog (IWDG)	22
3.14.5	System window watchdog (WWDG)	23

List of tables

Table 1.	Device summary	1
Table 2.	STM32F051xx family device features and peripheral count	11
Table 3.	Temperature sensor calibration values	18
Table 4.	Internal voltage reference calibration values	18
Table 5.	Capacitive sensing GPIOs available on STM32F051xx devices	20
Table 6.	Effective number of capacitive sensing channels on STM32F051xx	20
Table 7.	Timer feature comparison	21
Table 8.	Comparison of I ² C analog and digital filters	24
Table 9.	STM32F051xx I ² C implementation	24
Table 10.	STM32F051xx USART implementation	25
Table 11.	STM32F051xx SPI/I ² S implementation	26
Table 12.	Legend/abbreviations used in the pinout table	31
Table 13.	Pin definitions	31
Table 14.	Alternate functions selected through GPIOA_AFR registers for port A	37
Table 15.	Alternate functions selected through GPIOB_AFR registers for port B	38
Table 16.	STM32F051xx peripheral register boundary addresses	40
Table 17.	Voltage characteristics	45
Table 18.	Current characteristics	46
Table 19.	Thermal characteristics	46
Table 20.	General operating conditions	47
Table 21.	Operating conditions at power-up / power-down	48
Table 22.	Embedded reset and power control block characteristics	48
Table 23.	Programmable voltage detector characteristics	48
Table 24.	Embedded internal reference voltage	49
Table 25.	Typical and maximum current consumption from V _{DD} at 3.6 V	50
Table 26.	Typical and maximum current consumption from the V _{DDA} supply	51
Table 27.	Typical and maximum current consumption in Stop and Standby modes	52
Table 28.	Typical and maximum current consumption from the V _{BAT} supply	53
Table 29.	Typical current consumption, code executing from Flash memory, running from HSE 8 MHz crystal	54
Table 30.	Switching output I/O current consumption	56
Table 31.	Peripheral current consumption	57
Table 32.	Low-power mode wakeup timings	59
Table 33.	High-speed external user clock characteristics	59
Table 34.	Low-speed external user clock characteristics	60
Table 35.	HSE oscillator characteristics	61
Table 36.	LSE oscillator characteristics (f _{LSE} = 32.768 kHz)	62
Table 37.	HSI oscillator characteristics	64
Table 38.	HSI14 oscillator characteristics	65
Table 39.	LSI oscillator characteristics	66
Table 40.	PLL characteristics	66
Table 41.	Flash memory characteristics	66
Table 42.	Flash memory endurance and data retention	67
Table 43.	EMS characteristics	67
Table 44.	EMI characteristics	68
Table 45.	ESD absolute maximum ratings	69
Table 46.	Electrical sensitivities	69
Table 47.	I/O current injection susceptibility	70

In Standby mode, it is put in power down mode. In this mode, the regulator output is in high impedance and the kernel circuitry is powered down, inducing zero consumption (but the contents of the registers and SRAM are lost).

3.5.4 Low-power modes

The STM32F051xx microcontrollers support three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep mode**

In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

- **Stop mode**

Stop mode achieves very low power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low power mode.

The device can be woken up from Stop mode by any of the EXTI lines. The EXTI line source can be one of the 16 external lines, the PVD output, RTC, I2C1, USART1,, COMPx or the CEC.

The CEC, USART1 and I2C1 peripherals can be configured to enable the HSI RC oscillator so as to get clock for processing incoming data. If this is used when the voltage regulator is put in low power mode, the regulator is first switched to normal mode before the clock is provided to the given peripheral.

- **Standby mode**

The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the RTC domain and Standby circuitry.

The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pins, or an RTC event occurs.

Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.

3.6 Clocks and startup

System clock selection is performed on startup, however the internal RC 8 MHz oscillator is selected as default CPU clock on reset. An external 4-32 MHz clock can be selected, in which case it is monitored for failure. If failure is detected, the system automatically switches back to the internal RC oscillator. A software interrupt is generated if enabled. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example on failure of an indirectly used external crystal, resonator or oscillator).

Several prescalers allow the application to configure the frequency of the AHB and the APB domains. The maximum frequency of the AHB and the APB domains is 48 MHz.

can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

3.14.5 System window watchdog (WWDG)

The system window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the APB clock (PCLK). It has an early warning interrupt capability and the counter can be frozen in debug mode.

3.14.6 SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- a 24-bit down counter
- autoreload capability
- maskable system interrupt generation when the counter reaches 0
- programmable clock source (HCLK or HCLK/8)

3.15 Real-time clock (RTC) and backup registers

The RTC and the five backup registers are supplied through a switch that takes power either on V_{DD} supply when present or through the V_{BAT} pin. The backup registers are five 32-bit registers used to store 20 bytes of user application data when V_{DD} power is not present. They are not reset by a system or power reset, or at wake up from Standby mode.

The RTC is an independent BCD timer/counter. Its main features are the following:

- calendar with subseconds, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format
- automatic correction for 28, 29 (leap year), 30, and 31 day of the month
- programmable alarm with wake up from Stop and Standby mode capability
- on-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize the RTC with a master clock
- digital calibration circuit with 1 ppm resolution, to compensate for quartz crystal inaccuracy
- two anti-tamper detection pins with programmable filter. The MCU can be woken up from Stop and Standby modes on tamper event detection
- timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event. The MCU can be woken up from Stop and Standby modes on timestamp event detection
- reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision

3.18 Serial peripheral interface (SPI) / Inter-integrated sound interface (I²S)

Up to two SPIs are able to communicate up to 18 Mbit/s in slave and master modes in full-duplex and half-duplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame size is configurable from 4 bits to 16 bits.

One standard I²S interface (multiplexed with SPI1) supporting four different audio standards can operate as master or slave at half-duplex communication mode. It can be configured to transfer 16 and 24 or 32 bits with 16-bit or 32-bit data resolution and synchronized by a specific signal. Audio sampling frequency from 8 kHz up to 192 kHz can be set by an 8-bit programmable linear prescaler. When operating in master mode, it can output a clock for an external audio component at 256 times the sampling frequency.

Table 11. STM32F051xx SPI/I²S implementation

SPI features ⁽¹⁾	SPI1	SPI2
Hardware CRC calculation	X	X
Rx/Tx FIFO	X	X
NSS pulse mode	X	X
I ² S mode	X	-
TI mode	X	X

1. X = supported.

3.19 High-definition multimedia interface (HDMI) - consumer electronics control (CEC)

The device embeds a HDMI-CEC controller that provides hardware support for the Consumer Electronics Control (CEC) protocol (Supplement 1 to the HDMI standard).

This protocol provides high-level control functions between all audiovisual products in an environment. It is specified to operate at low speeds with minimum processing and memory overhead. It has a clock domain independent from the CPU clock, allowing the HDMI_CEC controller to wakeup the MCU from Stop mode on data reception.

3.20 Serial wire debug port (SW-DP)

An ARM SW-DP interface is provided to allow a serial wire debugging tool to be connected to the MCU.

Figure 4. UFBGA64 package pinout

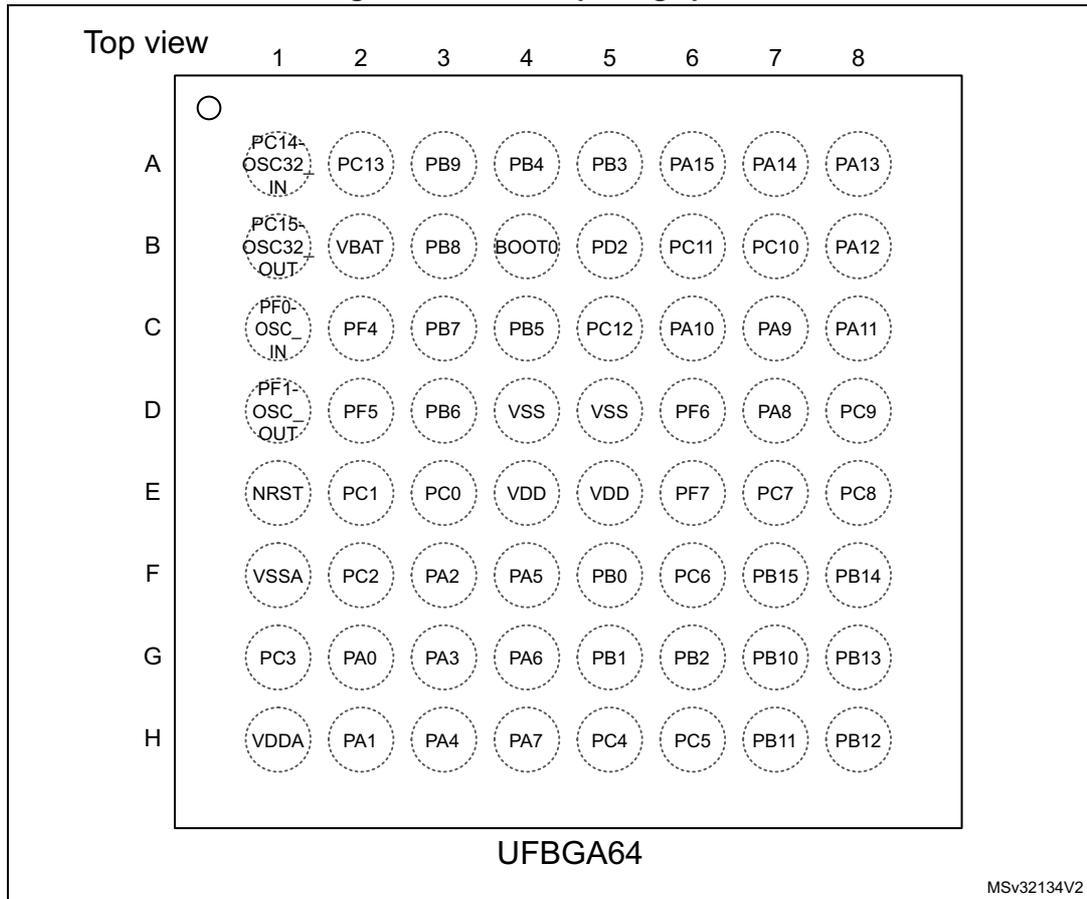


Figure 5. LQFP48 package pinout

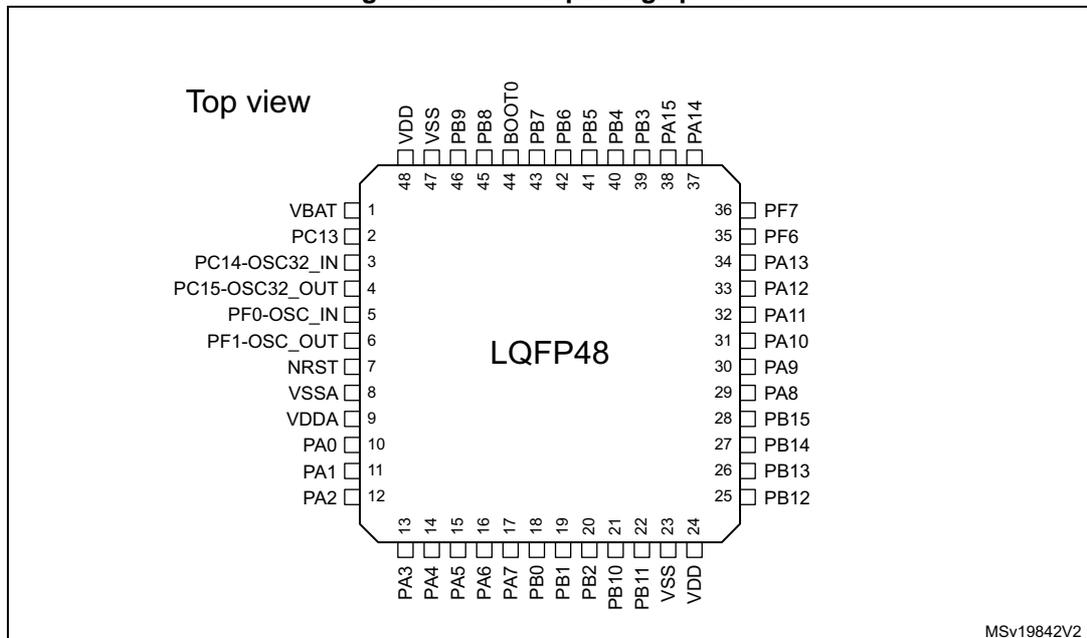


Table 13. Pin definitions (continued)

Pin number						Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	UFPGA64	LQFP48/UFQFPN48	WLCSP36	LQFP32	UFQFPN32					Alternate functions	Additional functions
22	G4	16	E3	12	12	PA6	I/O	TTa	-	SPI1_MISO, I2S1_MCK, TIM3_CH1, TIM1_BKIN, TIM16_CH1, COMP1_OUT, TSC_G2_IO3, EVENTOUT	ADC_IN6
23	H4	17	F4	13	13	PA7	I/O	TTa	-	SPI1_MOSI, I2S1_SD, TIM3_CH2, TIM14_CH1, TIM1_CH1N, TIM17_CH1, COMP2_OUT, TSC_G2_IO4, EVENTOUT	ADC_IN7
24	H5	-	-	-	-	PC4	I/O	TTa	-	EVENTOUT	ADC_IN14
25	H6	-	-	-	-	PC5	I/O	TTa	-	TSC_G3_IO1	ADC_IN15
26	F5	18	F3	14	14	PB0	I/O	TTa	-	TIM3_CH3, TIM1_CH2N, TSC_G3_IO2, EVENTOUT	ADC_IN8
27	G5	19	F2	15	15	PB1	I/O	TTa	-	TIM3_CH4, TIM14_CH1, TIM1_CH3N, TSC_G3_IO3	ADC_IN9
28	G6	20	D2	-	16	PB2	I/O	FT	(4)	TSC_G3_IO4	-
29	G7	21	-	-	-	PB10	I/O	FT	(5)	I2C2_SCL, CEC, TIM2_CH3, TSC_SYNC	-
30	H7	22	-	-	-	PB11	I/O	FT	(5)	I2C2_SDA, TIM2_CH4, TSC_G6_IO1, EVENTOUT	-
31	D4	23	F1	16	0	VSS	S	-	-	Ground	
32	E4	24	E1	17	17	VDD	S	-	-	Digital power supply	



Table 15. Alternate functions selected through GPIOB_AFR registers for port B

Pin name	AF0	AF1	AF2	AF3
PB0	EVENTOUT	TIM3_CH3	TIM1_CH2N	TSC_G3_IO2
PB1	TIM14_CH1	TIM3_CH4	TIM1_CH3N	TSC_G3_IO3
PB2				TSC_G3_IO4
PB3	SPI1_SCK, I2S1_CK	EVENTOUT	TIM2_CH2	TSC_G5_IO1
PB4	SPI1_MISO, I2S1_MCK	TIM3_CH1	EVENTOUT	TSC_G5_IO2
PB5	SPI1_MOSI, I2S1_SD	TIM3_CH2	TIM16_BKIN	I2C1_SMBA
PB6	USART1_TX	I2C1_SCL	TIM16_CH1N	TSC_G5_IO3
PB7	USART1_RX	I2C1_SDA	TIM17_CH1N	TSC_G5_IO4
PB8	CEC	I2C1_SCL	TIM16_CH1	TSC_SYNC
PB9	IR_OUT	I2C1_SDA	TIM17_CH1	EVENTOUT
PB10	CEC	I2C2_SCL	TIM2_CH3	TSC_SYNC
PB11	EVENTOUT	I2C2_SDA	TIM2_CH4	TSC_G6_IO1
PB12	SPI2_NSS	EVENTOUT	TIM1_BKIN	TSC_G6_IO2
PB13	SPI2_SCK		TIM1_CH1N	TSC_G6_IO3
PB14	SPI2_MISO	TIM15_CH1	TIM1_CH2N	TSC_G6_IO4
PB15	SPI2_MOSI	TIM15_CH2	TIM1_CH3N	TIM15_CH1N

Table 16. STM32F051xx peripheral register boundary addresses (continued)

Bus	Boundary address	Size	Peripheral
APB	0x4000 7C00 - 0x4000 7FFF	1 KB	Reserved
	0x4000 7800 - 0x4000 7BFF	1 KB	CEC
	0x4000 7400 - 0x4000 77FF	1 KB	DAC
	0x4000 7000 - 0x4000 73FF	1 KB	PWR
	0x4000 5C00 - 0x4000 6FFF	5 KB	Reserved
	0x4000 5800 - 0x4000 5BFF	1 KB	I2C2
	0x4000 5400 - 0x4000 57FF	1 KB	I2C1
	0x4000 4800 - 0x4000 53FF	3 KB	Reserved
	0x4000 4400 - 0x4000 47FF	1 KB	USART2
	0x4000 3C00 - 0x4000 43FF	2 KB	Reserved
	0x4000 3800 - 0x4000 3BFF	1 KB	SPI2
	0x4000 3400 - 0x4000 37FF	1 KB	Reserved
	0x4000 3000 - 0x4000 33FF	1 KB	IWDG
	0x4000 2C00 - 0x4000 2FFF	1 KB	WWDG
	0x4000 2800 - 0x4000 2BFF	1 KB	RTC
	0x4000 2400 - 0x4000 27FF	1 KB	Reserved
	0x4000 2000 - 0x4000 23FF	1 KB	TIM14
	0x4000 1400 - 0x4000 1FFF	3 KB	Reserved
	0x4000 1000 - 0x4000 13FF	1 KB	TIM6
	0x4000 0800 - 0x4000 0FFF	2 KB	Reserved
0x4000 0400 - 0x4000 07FF	1 KB	TIM3	
0x4000 0000 - 0x4000 03FF	1 KB	TIM2	

6.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in [Table 17: Voltage characteristics](#), [Table 18: Current characteristics](#) and [Table 19: Thermal characteristics](#) may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 17. Voltage characteristics⁽¹⁾

Symbol	Ratings	Min	Max	Unit
$V_{DD}-V_{SS}$	External main supply voltage	- 0.3	4.0	V
$V_{DDA}-V_{SS}$	External analog supply voltage	- 0.3	4.0	V
$V_{DD}-V_{DDA}$	Allowed voltage difference for $V_{DD} > V_{DDA}$	-	0.4	V
$V_{BAT}-V_{SS}$	External backup supply voltage	- 0.3	4.0	V
$V_{IN}^{(2)}$	Input voltage on FT and FTf pins	$V_{SS} - 0.3$	$V_{DDIOx} + 4.0^{(3)}$	V
	Input voltage on TTa pins	$V_{SS} - 0.3$	4.0	V
	BOOT0	0	9.0	V
	Input voltage on any other pin	$V_{SS} - 0.3$	4.0	V
$ \Delta V_{DDx} $	Variations between different V_{DD} power pins	-	50	mV
$ V_{SSx} - V_{SS} $	Variations between all the different ground pins	-	50	mV
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	see Section 6.3.12: Electrical sensitivity characteristics		-

1. All main power (V_{DD} , V_{DDA}) and ground (V_{SS} , V_{SSA}) pins must always be connected to the external power supply, in the permitted range.
2. V_{IN} maximum must always be respected. Refer to [Table 18: Current characteristics](#) for the maximum allowed injected current values.
3. Valid only if the internal pull-up/pull-down resistors are disabled. If internal pull-up or pull-down resistor is enabled, the maximum limit is 4 V.

Table 23. Programmable voltage detector characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _{PVD6}	PVD threshold 6	Rising edge	2.66	2.78	2.9	V
		Falling edge	2.56	2.68	2.8	V
V _{PVD7}	PVD threshold 7	Rising edge	2.76	2.88	3	V
		Falling edge	2.66	2.78	2.9	V
V _{PVDhyst} ⁽¹⁾	PVD hysteresis	-	-	100	-	mV
I _{DD(PVD)}	PVD current consumption	-	-	0.15	0.26 ⁽¹⁾	μA

1. Guaranteed by design, not tested in production.

6.3.4 Embedded reference voltage

The parameters given in [Table 24](#) are derived from tests performed under the ambient temperature and supply voltage conditions summarized in [Table 20: General operating conditions](#).

Table 24. Embedded internal reference voltage

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _{REFINT}	Internal reference voltage	-40 °C < T _A < +105 °C	1.2	1.23	1.25	V
t _{START}	ADC_IN17 buffer startup time	-	-	-	10 ⁽¹⁾	μs
t _{S_vrefint}	ADC sampling time when reading the internal reference voltage	-	4 ⁽¹⁾	-	-	μs
ΔV _{REFINT}	Internal reference voltage spread over the temperature range	V _{DDA} = 3 V	-	-	10 ⁽¹⁾	mV
T _{Coeff}	Temperature coefficient	-	- 100 ⁽¹⁾	-	100 ⁽¹⁾	ppm/°C

1. Guaranteed by design, not tested in production.

6.3.5 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.

The current consumption is measured as described in [Figure 14: Current consumption measurement scheme](#).

All Run-mode current consumption measurements given in this section are performed with a reduced code that gives a consumption equivalent to CoreMark code.

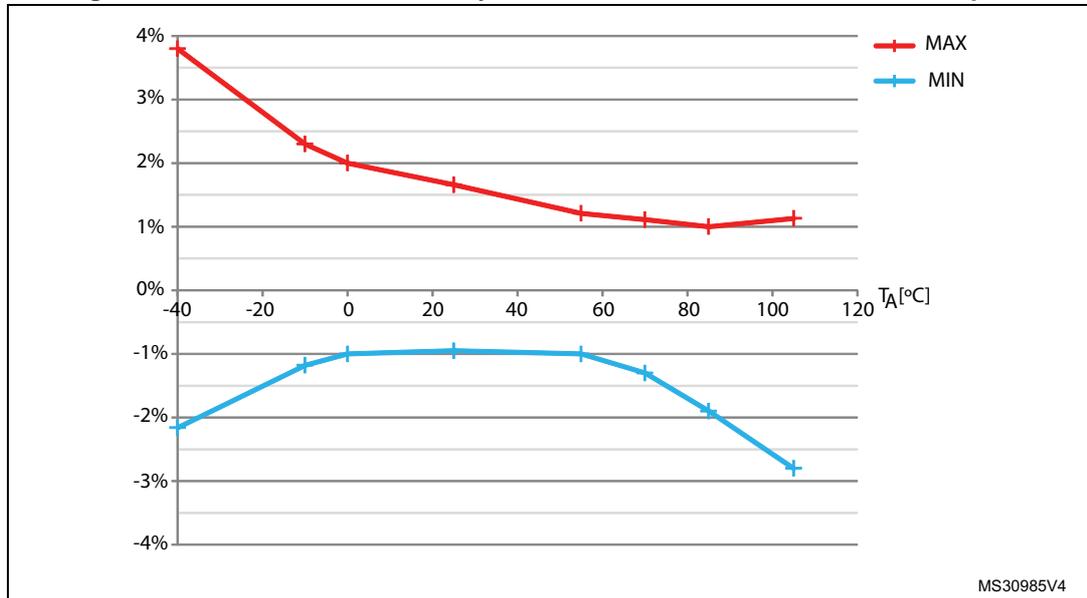
High-speed internal (HSI) RC oscillator

Table 37. HSI oscillator characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f _{HSI}	Frequency	-	-	8	-	MHz
TRIM	HSI user trimming step	-	-	-	1 ⁽²⁾	%
DuCy _(HSI)	Duty cycle	-	45 ⁽²⁾	-	55 ⁽²⁾	%
ACC _{HSI}	Accuracy of the HSI oscillator	T _A = -40 to 105°C	-2.8 ⁽³⁾	-	3.8 ⁽³⁾	%
		T _A = -10 to 85°C	-1.9 ⁽³⁾	-	2.3 ⁽³⁾	
		T _A = 0 to 85°C	-1.9 ⁽³⁾	-	2 ⁽³⁾	
		T _A = 0 to 70°C	-1.3 ⁽³⁾	-	2 ⁽³⁾	
		T _A = 0 to 55°C	-1 ⁽³⁾	-	2 ⁽³⁾	
t _{su(HSI)}	HSI oscillator startup time	-	1 ⁽²⁾	-	2 ⁽²⁾	µs
I _{DDA(HSI)}	HSI oscillator power consumption	-	-	80	100 ⁽²⁾	µA

1. V_{DDA} = 3.3 V, T_A = -40 to 105°C unless otherwise specified.
2. Guaranteed by design, not tested in production.
3. Data based on characterization results, not tested in production.
4. Factory calibrated, parts not soldered.

Figure 19. HSI oscillator accuracy characterization results for soldered parts



MS30985V4

High-speed internal 14 MHz (HSI14) RC oscillator (dedicated to ADC)

Table 38. HSI14 oscillator characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSI14}	Frequency	-	-	14	-	MHz
TRIM	HSI14 user-trimming step	-	-	-	1 ⁽²⁾	%
$DuCy_{(HSI14)}$	Duty cycle	-	45 ⁽²⁾	-	55 ⁽²⁾	%
ACC_{HSI14}	Accuracy of the HSI14 oscillator (factory calibrated)	$T_A = -40$ to 105 °C	-4.2 ⁽³⁾	-	5.1 ⁽³⁾	%
		$T_A = -10$ to 85 °C	-3.2 ⁽³⁾	-	3.1 ⁽³⁾	%
		$T_A = 0$ to 70 °C	-2.5 ⁽³⁾	-	2.3 ⁽³⁾	%
		$T_A = 25$ °C	-1	-	1	%
$t_{su(HSI14)}$	HSI14 oscillator startup time	-	1 ⁽²⁾	-	2 ⁽²⁾	µs
$I_{DDA(HSI14)}$	HSI14 oscillator power consumption	-	-	100	150 ⁽²⁾	µA

1. $V_{DDA} = 3.3$ V, $T_A = -40$ to 105 °C unless otherwise specified.
2. Guaranteed by design, not tested in production.
3. Data based on characterization results, not tested in production.

Figure 20. HSI14 oscillator accuracy characterization results

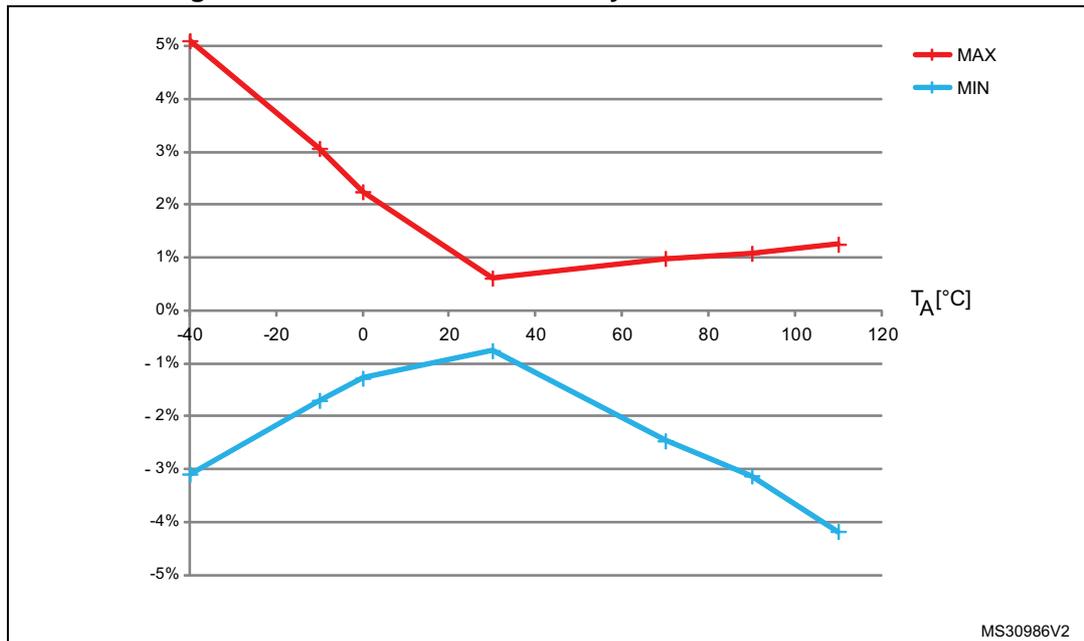
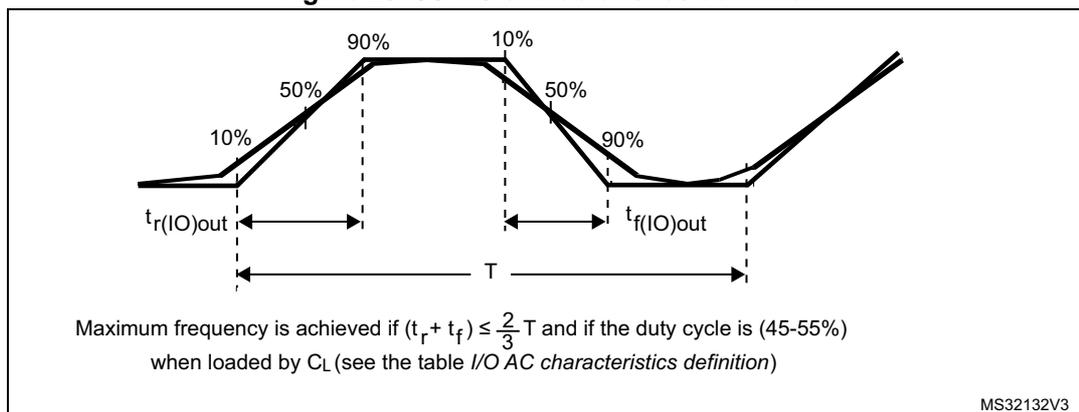


Figure 23. I/O AC characteristics definition



6.3.15 NRST pin characteristics

The NRST pin input driver uses the CMOS technology. It is connected to a permanent pull-up resistor, R_{PU} .

Unless otherwise specified, the parameters given in the table below are derived from tests performed under the ambient temperature and supply voltage conditions summarized in [Table 20: General operating conditions](#).

Table 51. NRST pin characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL(NRST)}$	NRST input low level voltage	-	-	-	$0.3 V_{DD} + 0.07^{(1)}$	V
$V_{IH(NRST)}$	NRST input high level voltage	-	$0.445 V_{DD} + 0.398^{(1)}$	-	-	
$V_{hys(NRST)}$	NRST Schmitt trigger voltage hysteresis	-	-	200	-	mV
R_{PU}	Weak pull-up equivalent resistor ⁽²⁾	$V_{IN} = V_{SS}$	25	40	55	kΩ
$V_F(NRST)$	NRST input filtered pulse	-	-	-	$100^{(1)}$	ns
$V_{NF(NRST)}$	NRST input not filtered pulse	$2.7 < V_{DD} < 3.6$	$300^{(3)}$	-	-	ns
		$2.0 < V_{DD} < 3.6$	$500^{(3)}$	-	-	

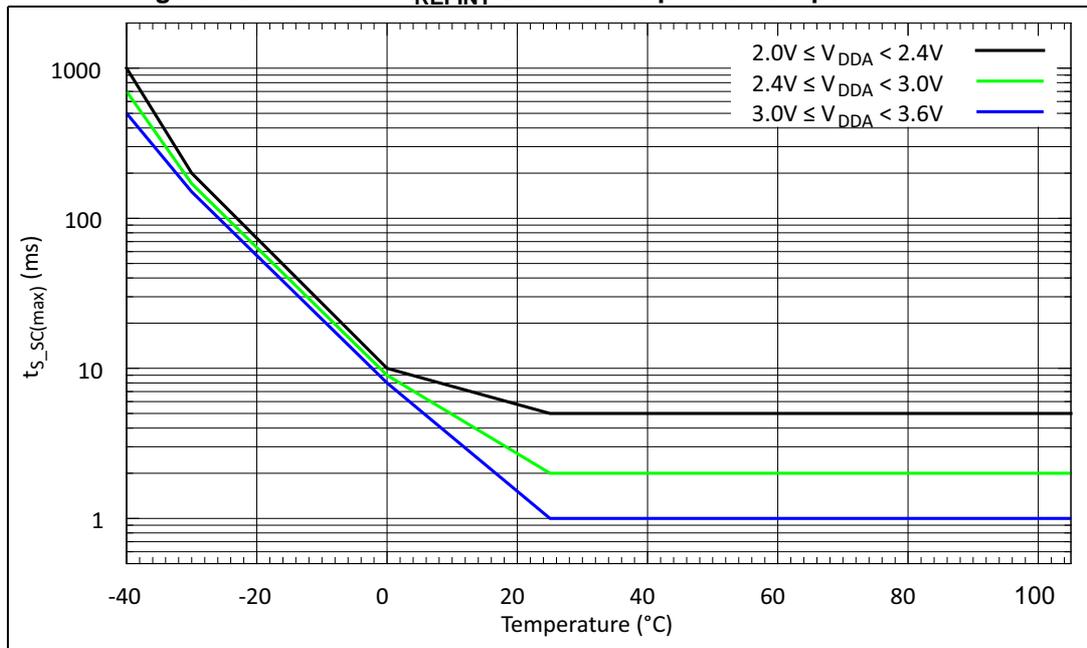
1. Data based on design simulation only. Not tested in production.
2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is minimal (~10% order).
3. Data based on design simulation only. Not tested in production.

Table 56. Comparator characteristics (continued)

Symbol	Parameter	Conditions	Min ⁽¹⁾	Typ	Max ⁽¹⁾	Unit	
V _{hys}	Comparator hysteresis	No hysteresis (COMPxHYST[1:0]=00)	-	0	-	mV	
		Low hysteresis (COMPxHYST[1:0]=01)	High speed mode	3	8		13
			All other power modes	5			10
		Medium hysteresis (COMPxHYST[1:0]=10)	High speed mode	7	15		26
			All other power modes	9			19
		High hysteresis (COMPxHYST[1:0]=11)	High speed mode	18	31		49
			All other power modes	19			40

1. Data based on characterization results, not tested in production.
2. For more details and conditions see [Figure 28: Maximum V_{REFINT} scaler startup time from power down](#).

Figure 28. Maximum V_{REFINT} scaler startup time from power down



6.3.19 Temperature sensor characteristics

Table 57. TS characteristics

Symbol	Parameter	Min	Typ	Max	Unit
$T_L^{(1)}$	V_{SENSE} linearity with temperature	-	± 1	± 2	$^{\circ}\text{C}$
Avg_Slope ⁽¹⁾	Average slope	4.0	4.3	4.6	mV/ $^{\circ}\text{C}$
V_{30}	Voltage at 30 $^{\circ}\text{C}$ (± 5 $^{\circ}\text{C}$) ⁽²⁾	1.34	1.43	1.52	V
$t_{START}^{(1)}$	ADC_IN16 buffer startup time	-	-	10	μs
$t_{S_temp}^{(1)}$	ADC sampling time when reading the temperature	4	-	-	μs

1. Guaranteed by design, not tested in production.
2. Measured at $V_{DDA} = 3.3 \text{ V} \pm 10 \text{ mV}$. The V_{30} ADC conversion result is stored in the TS_CAL1 byte. Refer to [Table 3: Temperature sensor calibration values](#).

6.3.20 V_{BAT} monitoring characteristics

Table 58. V_{BAT} monitoring characteristics

Symbol	Parameter	Min	Typ	Max	Unit
R	Resistor bridge for V_{BAT}	-	2 x 50	-	k Ω
Q	Ratio on V_{BAT} measurement	-	2	-	-
$E_r^{(1)}$	Error on Q	-1	-	+1	%
$t_{S_vbat}^{(1)}$	ADC sampling time when reading the V_{BAT}	4	-	-	μs

1. Guaranteed by design, not tested in production.

6.3.21 Timer characteristics

The parameters given in the following tables are guaranteed by design.

Refer to [Section 6.3.14: I/O port characteristics](#) for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

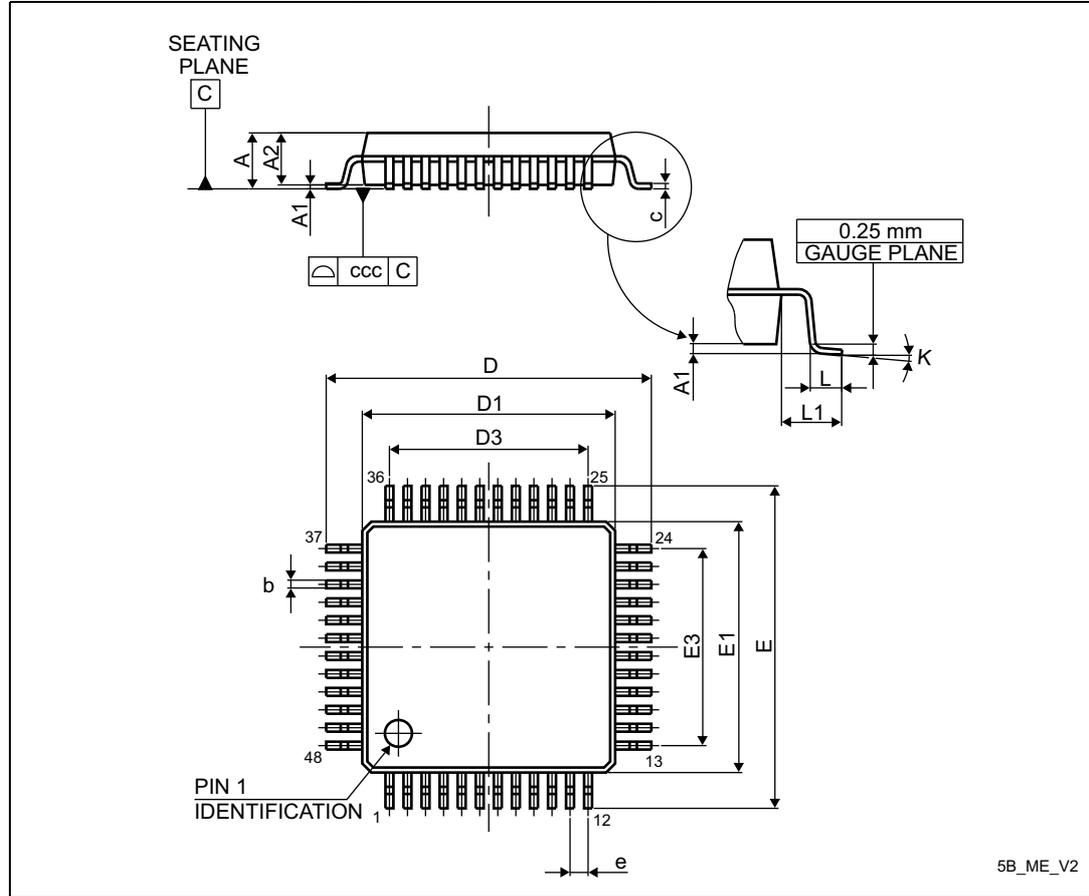
Table 59. TIMx characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{res(TIM)}$	Timer resolution time	-	-	1	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 48 \text{ MHz}$	-	20.8	-	ns
f_{EXT}	Timer external clock frequency on CH1 to CH4	-	-	$f_{TIMxCLK}/2$	-	MHz
		$f_{TIMxCLK} = 48 \text{ MHz}$	-	24	-	MHz
t_{MAX_COUNT}	16-bit timer maximum period	-	-	2^{16}	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 48 \text{ MHz}$	-	1365	-	μs
	32-bit counter maximum period	-	-	2^{32}	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 48 \text{ MHz}$	-	89.48	-	s

7.3 LQFP48 package information

LQFP48 is a 48-pin, 7 x 7 mm low-profile quad flat package.

Figure 40. LQFP48 package outline

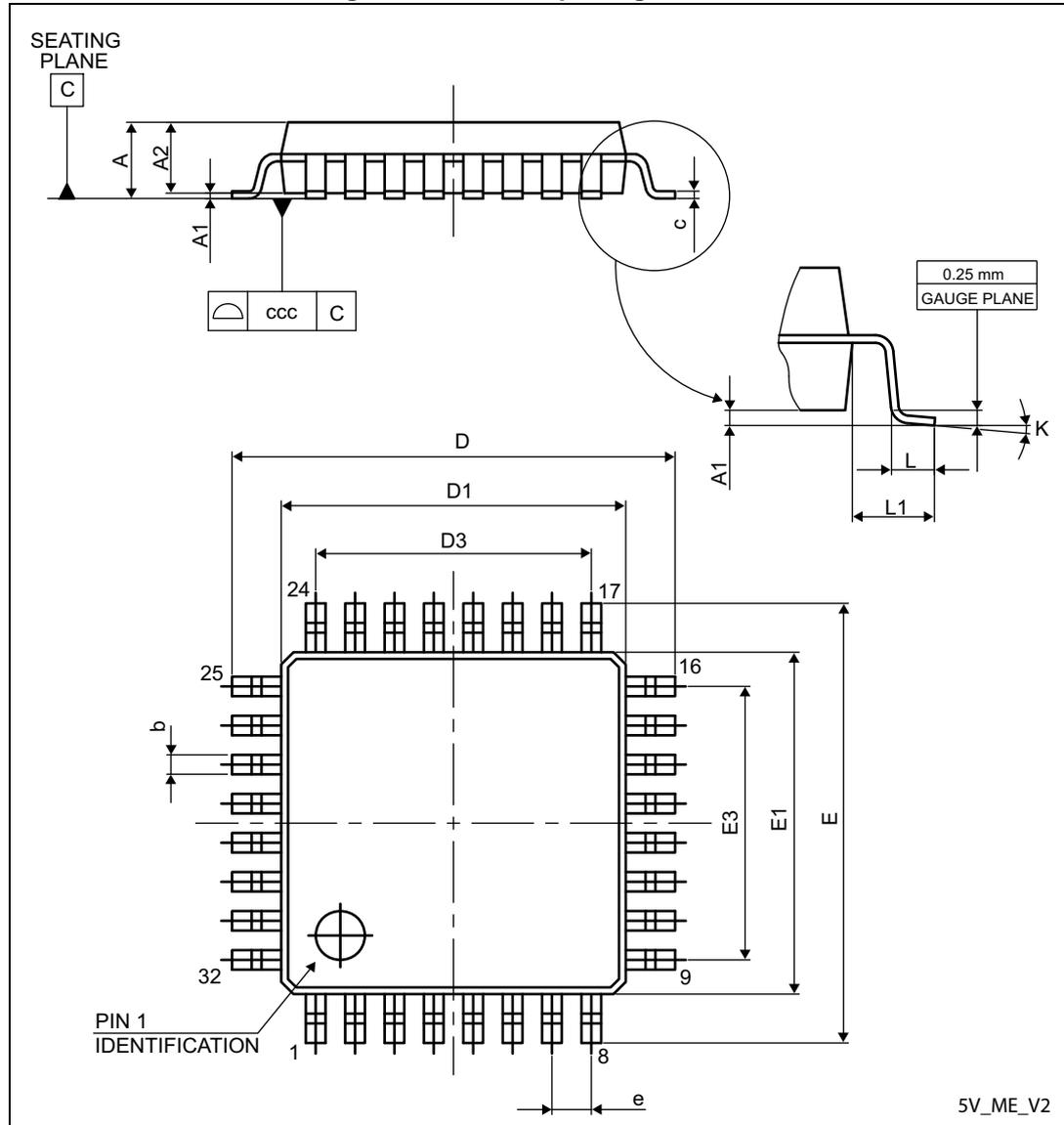


1. Drawing is not to scale.

7.6 LQFP32 package information

LQFP32 is a 32-pin, 7 x 7 mm low-profile quad flat package.

Figure 49. LQFP32 package outline



5V_ME_V2

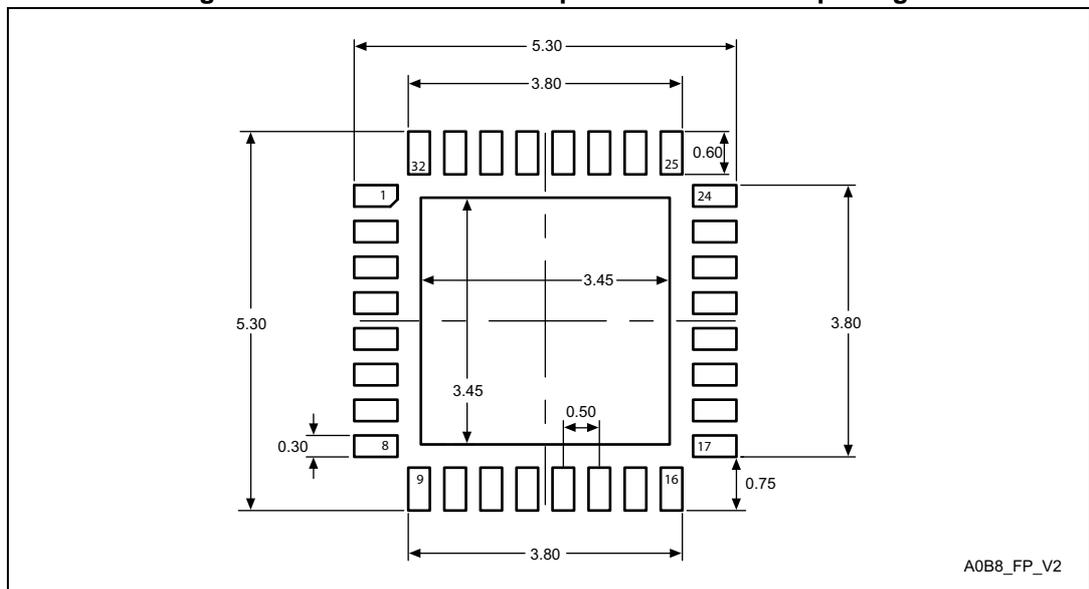
1. Drawing is not to scale.

Table 73. UFQFPN32 package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020
A3	-	0.152	-	-	0.0060	-
b	0.180	0.230	0.280	0.0071	0.0091	0.0110
D	4.900	5.000	5.100	0.1929	0.1969	0.2008
D1	3.400	3.500	3.600	0.1339	0.1378	0.1417
D2	3.400	3.500	3.600	0.1339	0.1378	0.1417
E	4.900	5.000	5.100	0.1929	0.1969	0.2008
E1	3.400	3.500	3.600	0.1339	0.1378	0.1417
E2	3.400	3.500	3.600	0.1339	0.1378	0.1417
e	-	0.500	-	-	0.0197	-
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
ddd	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 53. Recommended footprint for UFQFPN32 package



1. Dimensions are expressed in millimeters.

Table 76. Document revision history (continued)

Date	Revision	Changes
28-Aug-2015	5	<p>Updated the following:</p> <ul style="list-style-type: none"> – DAC and power management feature descriptions in <i>Features</i> – <i>Table 2: STM32F051xx family device features and peripheral count</i> – <i>Section 3.5.1: Power supply schemes</i> – <i>Figure 13: Power supply scheme</i> – <i>Table 17: Voltage characteristics</i> – <i>Table 20: General operating conditions</i>: updated the footnote for V_{IN} parameter – <i>Table 28: Typical and maximum current consumption from the V_{BAT} supply</i> – <i>Table 52: ADC characteristics</i> – <i>Table 33: High-speed external user clock characteristics</i>: replaced V_{DD} with V_{DDIOX} – <i>Table 34: Low-speed external user clock characteristics</i>: replaced V_{DD} with V_{DDIOX} – <i>Table 37: HSI oscillator characteristics</i> and <i>Figure 19: HSI oscillator accuracy characterization results for soldered parts</i> – <i>Table 38: HSI14 oscillator characteristics</i>: changed the min value for ACC_{HSI14} – <i>Table 41: Flash memory characteristics</i>: changed the values for t_{ME} and I_{DD} in write mode – <i>Table 43: EMS characteristics</i>: changed the value of V_{EFTB} – <i>Table 45: ESD absolute maximum ratings</i> – <i>Figure 10: STM32F051x8 memory map</i> – <i>Figure 21: TC and TTA I/O input characteristics</i> – <i>Figure 22: Five volt tolerant (FT and FTf) I/O input characteristics</i> – <i>Figure 23: I/O AC characteristics definition</i> – t_{START} definition in <i>Table 24: Embedded internal reference voltage</i> – t_{STAB} characteristics in <i>Table 52: ADC characteristics</i> – <i>Table 56: Comparator characteristics</i>: changed the description and values for V_{SC}, V_{DDA} and V_{REFINT} parameters. Added <i>Figure 28: Maximum V_{REFINT} scaler startup time from power down</i> – <i>Table 57: TS characteristics</i>: changed the min value for T_{S_temp} – <i>Table 58: V_{BAT} monitoring characteristics</i>: changed the min value for T_{S_vbat} and the typical value for R parameters – <i>Section 6.3.22: Communication interfaces</i>: updated the description and features in the subsection I²C interface characteristics – <i>Table 64: I²S characteristics</i>: updated the min values for data input hold time (master and slave receiver)